Notice of References Cited Application/Control No. 10/539,822 Examiner Mia M. Thomas Applicant(s)/Patent Under Reexamination FONDEUR ET AL. Page 1 of 1

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|--------------------|----------------|
| * | Α | US-5,963,679 | 10-1999 | Setlak, Dale R. | 382/312 |
| * | В | US-6,067,368 | 05-2000 | Setlak et al. | 382/124 |
| * | C | US-5,943,441 | 08-1999 | Michael, David | 382/199 |
| * | D | US-6,314,195 | 11-2001 | Fukuzumi, Shinichi | 382/115 |
| * | Е | US-6,438,257 | 08-2002 | Morimura et al. | 382/124 |
| * | F | US-6,052,475 | 04-2000 | Upton, Eric L. | 382/125 |
| * | G | US-6,292,576 | 09-2001 | Brownlee, Kenneth | 382/124 |
| * | Η | US-6,282,304 | 08-2001 | Novikov et al. | 382/125 |
| * | I | US-6,633,656 | 10-2003 | Picard, Francis | 382/124 |
| * | J | US-6,175,641 | 01-2001 | Kallo et al. | 382/124 |
| * | К | US-5,673,041 | 09-1997 | Chatigny et al. | 341/22 |
| * | L | US-6,647,133 | 11-2003 | Morita et al. | 382/124 |
| * | М | US-5,920,640 | 07-1999 | Salatino et al. | 382/124 |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|------|----------------|
| | N | | | | | |
| | 0 | | | | | |
| | Р | | | | | |
| | Ø | | | | | |
| | R | | | | | |
| | Ø | | | | | |
| | Т | | | | | |

NON-PATENT DOCUMENTS

| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) | | | |
|---|---|--|--|--|--|
| | U | Jarosz et al. "Large Scale Identification System Design", Chapter 9, pages 1-25 | | | |
| | V | Tartagni et al. "A fingerprint Sensor Based on the Feedback Capacitive Sensing Scheme", IEEE Journal of Solid State Circuits, Volume 33, No. 1, January 1998, pages 1-10 | | | |
| | w | | | | |
| | х | | | | |

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.